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PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

IN RE APPLICATION OF: Thomas L. Ritzdorf *et al.*
APPLICATION No.: 09/612,176
FILED: July 8, 2000
FOR: **APPARATUS AND METHOD FOR
PROCESSING A MICROELECTRONIC
WORKPIECE USING METROLOGY**

EXAMINER: Zandra V. Smith
ART UNIT: 2877
CONF. No: 7779

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Amendment Under 37 C.F.R. § 1.111

Assistant Commissioner for Patents
Washington, D.C. 20231

Sir:

The present communication responds to the Office Action dated December 20, 2002 in the above-identified application. Please amend the application as follows. The attached Appendix presents a marked-up version of the changes made to the specification and claims by the current amendment.

In the Claims:

Please cancel claims 1, 4, 7-10, 17-19, 21, 22 and 27-30. Please amend claims 2, 3, 5, 6, 11-13 and 20 as follows, and add new claims 31-47. Following is a complete listing of the claims pending in the application, as amended:

1. (Cancelled)

B1

2. (Amended) A processing apparatus for processing a microelectronic workpiece, comprising:

an in-line metrology unit having a space for receiving a microelectronic workpiece for measuring a condition of a first layer on said microelectronic workpiece and generating a condition signal;

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